# FCC Part 15, Subpart B, Class B TEST REPORT

#### SHENZHEN LANGHENG ELECTRONIC CO., LTD

BC30 V2.0

Test Model: BC30 V2.0

Additional Model No: RC40 V2.0

Prepared for : SHENZHEN LANGHENG ELECTRONIC CO., LTD

Address : 8/F 2nd Building, DongFangMing Industrial

Center, 33rd District, Bao'an, Shenzhen 518133,

China.

Prepared by : Shenzhen LCS Compliance Testing Laboratory Ltd.

Address : 101, 601, Xingyuan Industrial Park, Gushu

Community, Xixiang Street, Bao'an District,

Shenzhen, Guangdong, China

Tel : (+86)755-82591330 Fax : (+86)755-82591332 Web : www.LCS-cert.com

Mail : webmaster@LCS-cert.com

Date of receipt of test sample : September 23, 2019

Number of tested samples : 1

Serial number : Prototype

Date of Test : September 23, 2019 ~ September 29, 2019

Date of Report : October 17, 2019



## FCC TEST REPORT FCC Part 15, Subpart B, Class B(sDoC)

Report Reference No. .....:: LCS190920076AE

Date Of Issue .....: October 17, 2019

Testing Laboratory Name ....: Shenzhen LCS Compliance Testing Laboratory Ltd.

Address ..... : 101, 601, Xingyuan Industrial Park, Gushu Community,

Xixiang Street, Bao'an District, Shenzhen, Guangdong,

China

Testing Location/ Procedure ... : Full application of Harmonised standards ■

Partial application of Harmonised standards

Other standard testing method

Applicant's Name .....: SHENZHEN LANGHENG ELECTRONIC CO., LTD

Address ...... : 8/F 2nd Building, DongFangMing Industrial Center,33rd

District, Bao'an, Shenzhen 518133, China.

**Test Specification** 

Standard......: FCC Part 15, Subpart B, Class B(sDoC), ANSI C63.4 -2014

Test Report Form No. .....: LCSEMC-1.0

TRF Originator.....: Shenzhen LCS Compliance Testing Laboratory Ltd.

Master TRF .....: Dated 2011-03

#### SHENZHEN LCS COMPLIANCE TESTING LABORATORY LTD. All rights reserved.

This publication may be reproduced in whole or in part for non-commercial purposes as long as the SHENZHEN LCS COMPLIANCE TESTING LABORATORY LTD. is acknowledged as copyright owner and source of the material. SHENZHEN LCS COMPLIANCE TESTING LABORATORY LTD. takes no responsibility for and will not assume liability for damages resulting from the reader's interpretation of the reproduced material due to its placement and context.

Test Item Description.....: BC30 V2.0

Trade Mark.....: FENIX

Test Model .....: BC30 V2.0

Result .....: : Positive

Compiled by: Supervised by:

Approved by:

Ray Yang / File administrators

Aking Jin / Technique principal

Aking Jin

Gavin Liang/ Manager

# **FCC -- TEST REPORT**

Test Report No.: LCS190920076AE October 17, 2019

Date of issue

| Test Model                                | : BC30 V2.0   |
|---|---|
| EUT                                       | : BC30 V2.0   |
|   |   |
| Applicant                                 | : SHENZHEN LANGHENG ELECTRONIC CO., LTD   |
| Address                                   | : 8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.   |
|   | •   |
| Telephone                                 | : /   |
| Fax                                       | : /   |
|   |   |
|   |   |
| Manufacturor                              | · SUENZUEN I ANGUENG EI ECTDONIC CO I TD  |
|   | : SHENZHEN LANGHENG ELECTRONIC CO., LTD   |
|   | <ul><li>: SHENZHEN LANGHENG ELECTRONIC CO., LTD</li><li>: 8/F 2nd Building, DongFangMing Industrial Center,33rd</li></ul>   |
|   | •   |
| Address                                   | : 8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.   |
| Address Telephone                         | <ul><li>8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.</li><li>/</li></ul>   |
| Address                                   | <ul><li>8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.</li><li>/</li></ul>   |
| Address Telephone Fax                     | <ul> <li>8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.</li> <li>/</li> <li>/</li> </ul>   |
| Address Telephone Fax Factory             | <ul> <li>8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.</li> <li>/</li> <li>/</li> <li>/</li> </ul>  |
| Address Telephone Fax                     | <ul> <li>8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.</li> <li>/</li> <li>/</li> <li>/</li> </ul>  |
| Address Telephone Fax Factory             | <ul> <li>8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.</li> <li>/</li> <li>/</li> <li>/</li> <li>/</li> <li>/</li> </ul>                                  |
| Address  Telephone  Fax  Factory  Address | <ul> <li>8/F 2nd Building, DongFangMing Industrial Center,33rd District, Bao'an, Shenzhen 518133, China.</li> <li>/</li> <li>/</li> <li>/</li> <li>/</li> <li>/</li> <li>/</li> <li>/</li> <li>/</li> </ul> |

## Test Result according to the standards on page 6: Positive

The test report merely corresponds to the test sample.

It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

# **Revision History**

| Rev | rision | Issue Date       | Revisions     | Revised By  |
|-----|--------|------------------|---------------|-------------|
| 0   | 00     | October 17, 2019 | Initial Issue | Gavin Liang |
|     |        |                  |               |             |
|     |        |                  |               |             |

### **TABLE OF CONTENTS**

| Test Report Description                       | Page |
|---|------|
| 1. SUMMARY OF STANDARDS AND RESULTS           | 6    |
| 1.1. Description of Standards and Results     | 6    |
| 2. GENERAL INFORMATION                        | 7    |
| 2.1. Description of Device (EUT)              |      |
| 2.2. Description of Test Facility             |      |
| 2.3. Statement of the Measurement Uncertainty | 7    |
| 2.4. Measurement Uncertainty                  | 8    |
| 3. TEST RESULTS                               | 9    |
| 3.1.Radiated Emission Measurement             | 9    |
| 4. PHOTOGRAPHS OF TEST SETUP                  | 13   |
| 5 EXTERNAL AND INTERNAL PHOTOS OF THE FUT     | 14   |

# 1. SUMMARY OF STANDARDS AND RESULTS

## 1.1. Description of Standards and Results

The EUT have been tested according to the applicable standards as referenced below.

| EMISSION                                  |  |         |         |  |  |
|---|--|---------|---------|--|--|
| Description of Test Item                  | Standard   | Limits  | Results |  |  |
| Conducted disturbance at mains terminals  | FCC Part 15, Subpart B, Class B(sDoC),<br>ANSI C63.4 -2014 | Class B | N/A     |  |  |
| Radiated disturbance                      | FCC Part 15, Subpart B, Class B(sDoC),<br>ANSI C63.4 -2014 | Class B | PASS    |  |  |
| N/A is an abbreviation for Not Applicable |  |         |         |  |  |

| Test mode: |         |        |
|------------|---------|--------|
| Mode 1     | Working | Record |

#### 2. GENERAL INFORMATION

2.1. Description of Device (EUT)

EUT : BC30 V2.0

Trade Mark : FENIX

Test Model : BC30 V2.0

Additional Model : RC40 V2.0

Model Declaration : PCB board, structure and internal of these model(s) are

the same, So no additional models were tested

Power Supply: Input: DC 7.2V, 1.2A

Output: DC 6V, 1.3A

EUT Clock Frequency: ≤108MHz

#### 2.2. Description of Test Facility

Site Description

EMC Lab. : FCC Registration Number is 254912.

Industry Canada Registration Number is 9642A-1.

ESMD Registration Number is ARCB0108.

UL Registration Number is 100571-492.

TUV SUD Registration Number is SCN1081.

TUV RH Registration Number is UA 50296516-001.

NVLAP Registration Code is 600167-0.

## 2.3. Statement of the Measurement Uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. To CISPR 16 – 4 "Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements" and is documented in the LCS quality system acc. To DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

## 2.4. Measurement Uncertainty

| Test                  | Parameters  | Expanded Uncertainty (U <sub>lab</sub> ) | Expanded Uncertainty (U <sub>cispr</sub> ) |
|-----------------------|---|--|--|
| Conducted<br>Emission | Level accuracy<br>(9kHz to 150kHz)<br>(150kHz to 30MHz) | ± 2.63 dB<br>± 2.35 dB                   | $\pm$ 3.8 dB $\pm$ 3.4 dB                  |
| Radiated Emission     | Level accuracy<br>(30MHz to 1000MHz)                    | ± 3.48 dB                                | ± 5.3 dB                                   |
| Radiated Emission     | Level accuracy (above 1000MHz)                          | ± 3.90 dB                                | ± 5.2 dB                                   |

- (1) Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the apparatus.
- (2) The reported expanded uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor of k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

### 3. TEST RESULTS

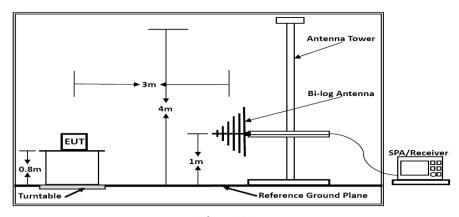
### 3.1.Radiated Emission Measurement

### 3.1.1. Test Equipment

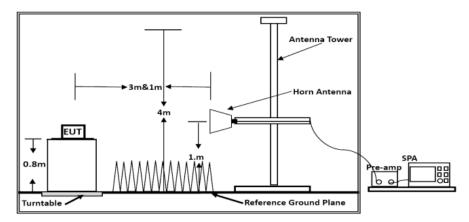
The following test equipments are used during the radiated emission measurement:

| Item | Equipment                   | Manufacturer      | Model No.       | Serial No. | Last Cal.  |
|------|-----------------------------|-------------------|-----------------|------------|------------|
| 1    | EMI Test Software           | AUDIX             | E3              | /          | N/A        |
| 2    | 3m Semi Anechoic<br>Chamber | SIDT<br>FRANKONIA | SAC-3M          | 03CH03-HY  | 2019-06-12 |
| 3    | Positioning<br>Controller   | MF                | MF-7082         | /          | 2019-06-12 |
| 4    | By-log Antenna              | SCHWARZBECK       | VULB9163        | 9163-470   | 2019-07-25 |
| 5    | Horn Antenna                | SCHWARZBECK       | BBHA 9120D      | 9120D-1925 | 2019-07-01 |
| 6    | EMI Test Receiver           | R&S               | ESR 7           | 101181     | 2019-06-12 |
| 7    | RS SPECTRUM<br>ANALYZER     | R&S               | FSP40           | 100503     | 2018-11-15 |
| 8    | Broadband<br>Preamplifier   | /                 | BP-01M18G       | P190501    | 2019-07-01 |
| 9    | RF Cable-R03m               | Jye Bao           | RG142           | CB021      | 2019-06-12 |
| 10   | RF Cable-HIGH               | SUHNER            | SUCOFLEX<br>106 | 03CH03-HY  | 2019-06-12 |

## 3.1.2. Block Diagram of Test Setup



Below 1GHz



Above 1GHz

#### 3.1.3. Radiated Emission Limit (Class B)

Limits for Radiated Disturbance Below 1GHz

| FREQUENCY  | DISTANCE | FIELD STRENGTHS LIMIT |          |
|------------|----------|-----------------------|----------|
| MHz        | Meters   | μV/m                  | dB(μV)/m |
| 30 ~ 88    | 3        | 100                   | 40       |
| 88 ~ 216   | 3        | 150                   | 43.5     |
| 216 ~ 960  | 3        | 200                   | 46       |
| 960 ~ 1000 | 3        | 500                   | 54       |

Remark: (1) Emission level (dB) $\mu$ V = 20 log Emission level  $\mu$ V/m

- (2) The smaller limit shall apply at the cross point between two frequency bands.
- (3) Distance is the distance in meters between the measuring instrument, antenna and the closest point of any part of the device or system.

| 1  |  |  |  |  |  |
|--|--|--|--|--|--|
| Limits for Radiated Emission Above 1GHz                      |  |  |  |  |  |
| Frequency Distance Peak Limit Average Limit                  |  |  |  |  |  |
| (MHz) (Meters) (dBμV/m) (dBμV/m)                             |  |  |  |  |  |
| Above 1000 3 74 54   |  |  |  |  |  |
| ***Note: The lower limit applies at the transition frequency |  |  |  |  |  |

#### 3.1.4. EUT Configuration on Measurement

The following equipment are installed on Radiated Emission Measurement to meet the commission requirements and operating regulations in a manner which tends to maximize its emission characteristics in normal application.

#### 3.1.5. Operating Condition of EUT

- 3.5.1. Setup the EUT as shown in Section 3.2.
- 3.5.2.Let the EUT work in test Mode 1 and measure it.

#### 3.1.6. Test Procedure

EUT and its simulators are placed on a turntable, which is 0.8 meter high above ground. The turntable can rotate 360 degrees to determine the position of the maximum emission level. EUT is set 3.0 meters away from the receiving antenna, which is mounted on a antenna tower. The antenna can be moved up and down between 1.0 meter and 4 meters to find out the maximum emission level. Broadband antenna (calibrated by-log antenna) is used as receiving antenna.

Both horizontal and vertical polarization of the antenna is set on measurement. In order to find the maximum emission levels, all of the interface cables must be manipulated according to ANSI C63.4-2009 on radiated emission measurement.

The bandwidth of the EMI test receiver is set at 120kHz, 300kHz.

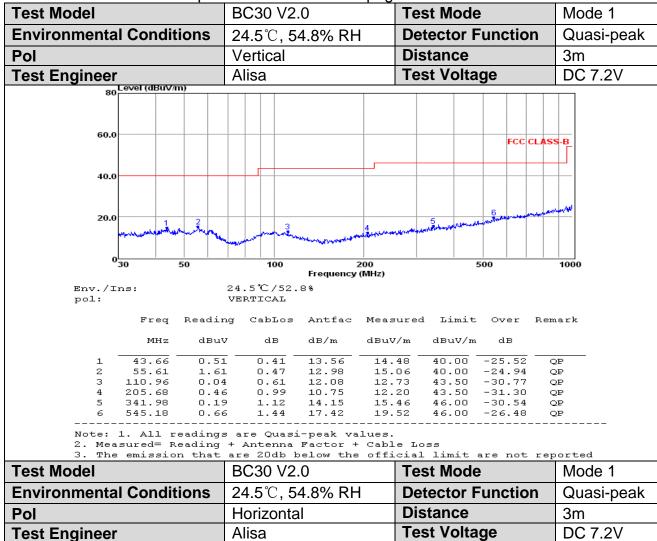
The frequency range from 30MHz to 1000MHz is checked.

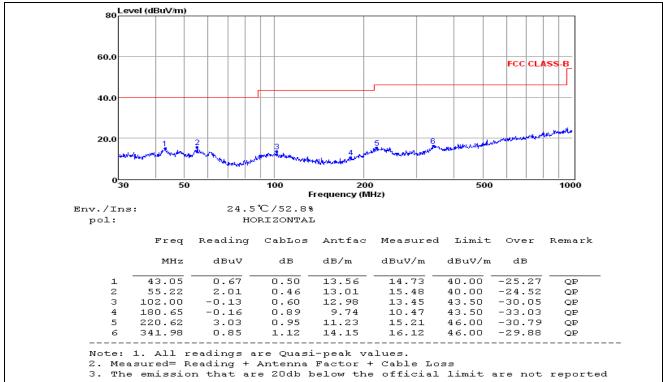
The frequency range from 1GHz to the frequency which about 5th carrier harmonic or 6GHz is checked.

#### 3.1.7. Test Results

#### PASS.

The test result please refer to the next page.





Note: Pre-Scan all mode, Thus record worse case mode result in this report.

# 4. PHOTOGRAPHS OF TEST SETUP

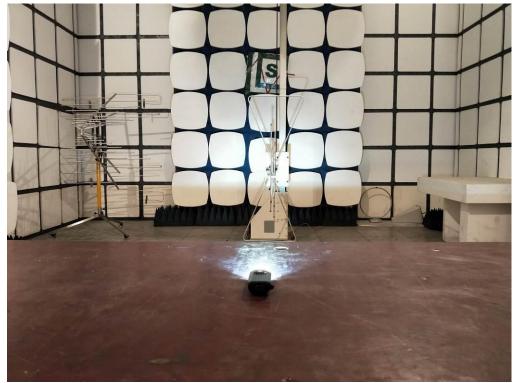


Photo of Radiated Measurement

# 5. EXTERNAL AND INTERNAL PHOTOS OF THE EUT



Fig. 1

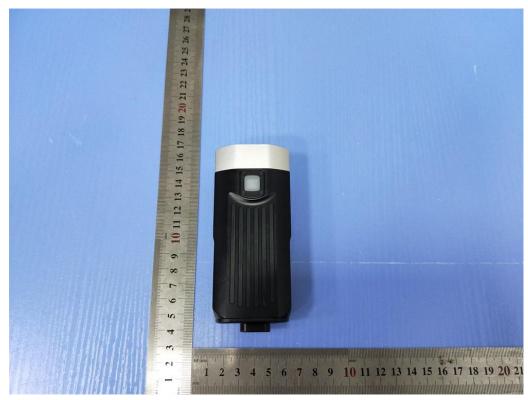


Fig. 2



Fig. 3

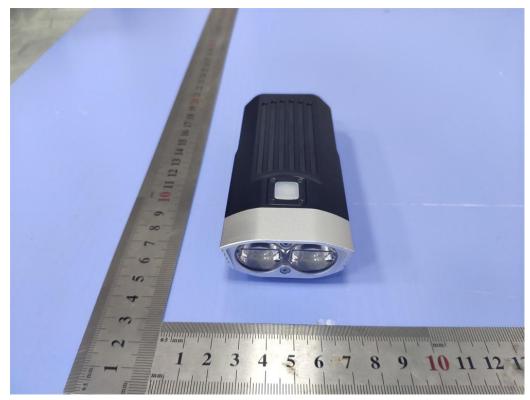


Fig. 4



Fig. 5



Fig. 6



Fig. 7

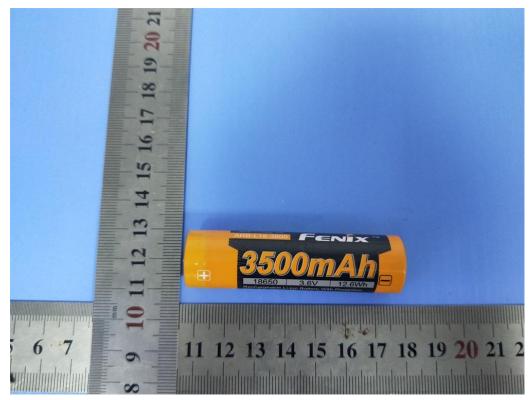


Fig. 8

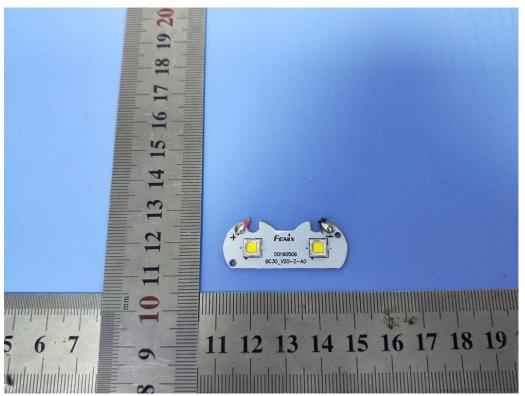


Fig. 9

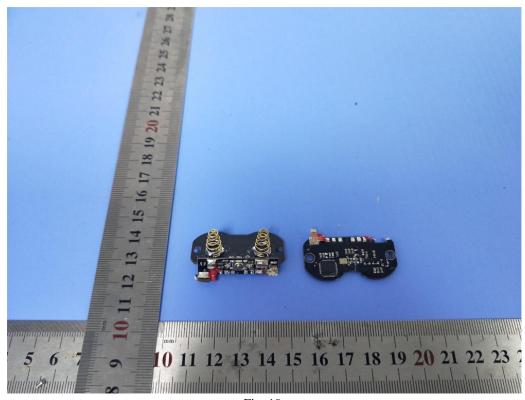


Fig. 10

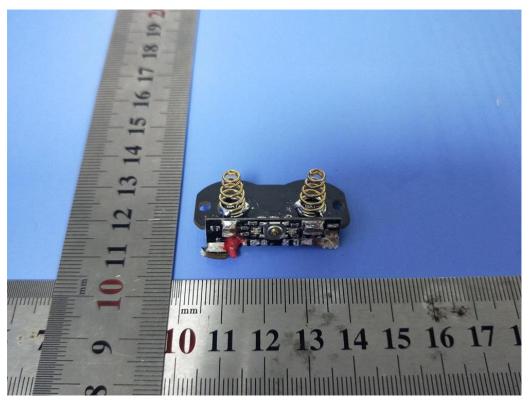


Fig. 11

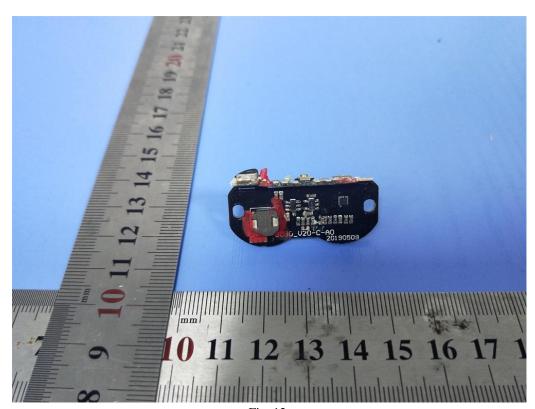


Fig. 12

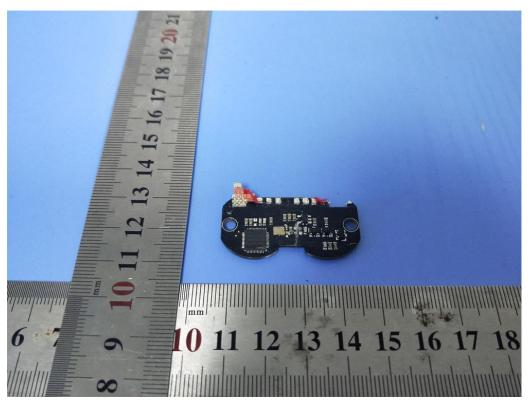


Fig. 13

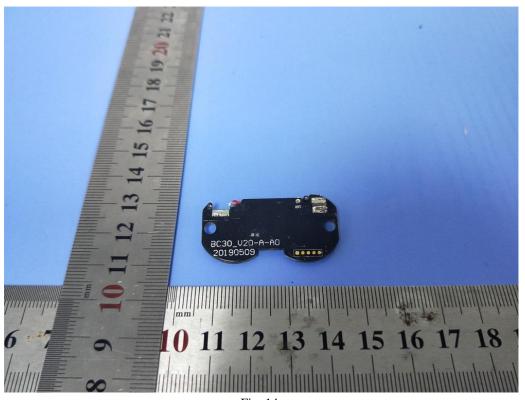


Fig. 14

# -----THE END OF TEST REPORT-----